



SEM image of a recessed electrode on the CMOS chip surface with indicated projected feature height h .

The figure above shows a measurement of the surface height of the CMOS chip. The height h was determined by acquiring an image under an angle of $\alpha = 40^\circ$. The true height h_t of the well was calculated in the following way:

$$h_t = \frac{h}{\sin(\alpha)} = \frac{1.402 \mu\text{m}}{\sin(40^\circ)} = 2.18 \mu\text{m} \quad (1)$$